MOSFET - Symmetrical Dual N-Channel 80 V, 18 mΩ, 26 A

NTTFD018N08LC

General Description

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q2) and synchronous (Q1) have been designed to provide optimal power efficiency.

Features

Q1: N-Channel

- Max $r_{DS(on)} = 18 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 7.8 \text{ A}$
- Max $r_{DS(on)}$ = 29 m Ω at V_{GS} = 4.5, I_D = 6.2 A

Q2: N-Channel

- Max $r_{DS(on)} = 18 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 7.8 \text{ A}$
- Max $r_{DS(on)} = 29 \text{ m}\Omega$ at $V_{GS} = 4.5$, $I_D = 6.2 \text{ A}$
- Low Inductance Packaging Shortens Rise/Fall Times, Resulting in Lower Switching Losses
- RoHS Compliant

Typical Applications

- 48 V Input Primary Half Bridge
- Communications
- General Purpose Point of Load

PIN DESCRIPTION

Pin	Name	Description
1, 11, 12	GND (LSS)	Low Side Source
2	LSG	Low Side Gate
3, 4, 5, 6	V + (HSD)	High Side Drain
7	HSG	High Side Gate
8, 9, 10	sw	Switching Node, Low Side Drain

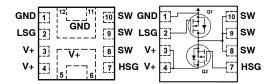


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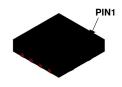
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
80 V	18 mΩ @ 10 V	26 A
80 V	29 mΩ @ 4.5 V	20 A

ELECTRICAL CONNECTION



Dual N-Channel MOSFET





Top

Bottom

Power Clip 33 Symmetric (WQFN12) CASE 510CJ

MARKING DIAGRAM

D018 AYWWZZ

D018 = Specific Device Code
A = Assembly Plant Code
Y = Numeric Year Code
WW = Work Week Code
ZZ = Assembly Lot Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ORDERING INFORMATION AND PACKAGE MARKING

Device	Marking	Package	Shipping [†]
NTTFD018N08LC	D018	WQFN12 (Pb-Free)	3000 Units/ Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MOSFET MAXIMUM RATINGS (T_A = 25°C, Unless otherwise specified)

Symbol		Paran	neter		Q1	Q2	Units
V_{DS}	Drain to Source	Voltage			80	80	V
V_{GS}	Gate to Source \	/oltage			±20	±20	V
I _D	Drain Current	-Continuous	T _C = 25°C	(Note 4)	26	26	Α
		-Continuous	T _C = 100°C	(Note 4)	16	16	
		-Continuous	T _A = 25°C		6 (Note 1a)	6 (Note 1b)	
		-Pulsed	T _A = 25°C		349	349	
E _{AS}	Single Pulse Ava	alanche Energy (L = 1 m	H, I _{L(pk)} = 8 A)	(Note 3)	32	32	mJ
P_{D}	Power Dissipation	n for Single Operation	T _C = 25°C		26	26	W
	Power Dissipation	n for Single Operation	T _A = 25°C		1.7 (Note 1a)	1.7 (Note 1b)	
I _S	Source Current (Body Diode)			21	21	Α
T _J , T _{STG}	Operating and Storage Junction Temperature Range		–55 to	+150	°C		
TL	Lead Temperatu	re for Soldering Purpose	es (1/8" from case for 10 s)		260	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Q1	Q2	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	4.8	4.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	70 (Note 1a)	70 (Note 1b)	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	135 (Note 1c)	135 (Note 1c)	

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min.	Тур.	Max.	Units
OFF CHAR	OFF CHARACTERISTICS						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$	Q1	80			V
		$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$	Q2	80			
ΔBV_{DSS}	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C	Q1		76.81		mV/°C
ΔT_J	Coefficient	I _D = 250 μA, referenced to 25°C	Q2		76.81		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 64 V, V _{GS} = 0 V	Q1			1	μΑ
		V _{DS} = 64 V, V _{GS} = 0 V	Q2			1	
I _{GSS}	Gate to Source Leakage Current, Forward	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q1			±100	μΑ
		$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q2			±100	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

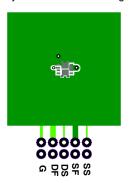
Symbol	Parameter	Test Conditions	Type	Min.	Тур.	Max.	Units
ON CHAR	ACTERISTICS						
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 44 \mu A$	Q1	1.0	1.5	2.5	٧
		$V_{GS} = V_{DS}$, $I_D = 44 \mu A$	Q2	1.0	1.5	2.5	1
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage	I _D = 44 μA, referenced to 25°C	Q1		-5.71		mV/°C
ΔT_{J}	Temperature Coefficient	I _D = 44 μA, referenced to 25°C	Q2		-5.71		1
r _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10 V, I _D = 7.8 A	Q1		15	18	mΩ
		V _{GS} = 4.5 V, I _D = 6.2 A			22	29	1
		$V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A},$ $T_J = 125^{\circ}\text{C}$			25		
r _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10 V, I _D = 7.8 A	Q2		15	18	mΩ
		V _{GS} = 4.5 V, I _D = 6.2 A			22	29	1
		$V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A},$ $T_J = 125^{\circ}\text{C}$			25		
9FS	Forward Transconductance	V _{DS} = 5 V, I _D = 7.8 A	Q1		23		S
		V _{DS} = 5 V, I _D = 7.8 A	Q2		23		1
DYNAMIC	CHARACTERISTICS						•
C _{ISS}	Input Capacitance	Q1:	Q1		856		pF
		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ Mhz}$	Q2		856		
C _{OSS}	Output Capacitance	acitance Q2:	Q1		230		pF
		V _{DS} = 40 V, V _{GS} = 0 V, f = 1 MHz	Q2		230		1
C _{RSS}	Reverse Transfer Capacitance	\exists	Q1		10		pF
			Q2		10		1
R _G	Gate Resistance	istance $T_A = 25^{\circ}C$			0.5		Ω
			Q2		0.5		1
SWITCHIN	G CHARACTERISTICS						
td _(ON)	Turn – On Delay Time	Q1:	Q1		9.4		ns
		V_{DD} = 40 V, V_{GS} = 4.5 V, I_{D} = 6.2 A, R_{GEN} = 6 Ω	Q2		9.4		1
t _r	Rise Time	Q2:	Q1		5.8		ns
		$V_{DD} = 40 \text{ V}, V_{GS} = 4.5 \text{ V},$	Q2		5.8		1
t _{D(OFF)}	Turn – Off Delay Time	I_D = 6.2 A, R_{GEN} = 6 Ω	Q1		14.6		ns
			Q2		14.6		1
t _f	Fall Time		Q1		5.5		ns
			Q2		5.5		1
Qg	Total Gate Charge	V _{GS} = 0V to 10 V	Q1		12.4		nC
			Q2		12.4		1
Qg	Total Gate Charge	V _{GS} = 0V to 4.5 V	Q1		6.0		nC
		Q1:	Q2		6.0		
Q _{gs}	Gate to Source Gate Charge	$V_{DD} = 40 \text{ V},$	Q1		1.94		nC
-		I _D = 6.2 A Q2:	Q2		1.94		
Q _{gd}	Gate to Drain "Miller" Charge	$V_{DD} = 40 \text{ V},$ $I_{D} = 6.2 \text{ A}$	Q1		1.71		nC
	_	ID - 0.2 A	1	I	1	I	1

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

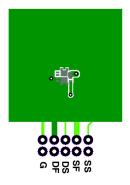
Symbol	Parameter	Test Conditions	Туре	Min.	Тур.	Max.	Units
DRAIN-SC	DURCE DIODE CHARACTERISTICS			•	•		
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 7.8 A (Note 2)	Q1		0.82	1.5	V
		V _{GS} = 0 V, I _S = 7.8 A (Note 2)	Q2		0.82	1.5	
t _{rr}	Reverse Recovery Time	Q1:	Q1		13.3		ns
		I _F = 7.8 A, di/dt = 300 A/μs	Q2		13.3		
Q _{rr}	Reverse Recovery Charge	Q2: I _F = 7.8 A, di/dt = 300 A/μs	Q1		18.1		nC
			Q2		18.1		
t _{rr}	Reverse Recovery Time	Q1:	Q1		10.3		ns
		I _F = 7.8 A, di/dt = 1000 A/μs	Q2		10.3		
Q _{rr}	Reverse Recovery Charge Q2:	I _F = 7.8 A, di/dt = 1000 A/μs	Q1		51		nC
			Q2		51		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 \times 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



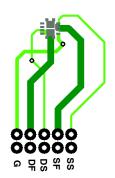
a) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



c) 135°C/W when mounted on a minimum pad of 2 oz copper.



d) 135°C/W when mounted on a minimum pad of 2 oz copper.

- Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.
 Q1: E_{AS} of 32 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 8 A, V_{DD} = 80 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 8.2 A. Q2: E_{AS} of 32 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 8 A, V_{DD} = 80 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 8.2 A.
 Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal
- & electro-mechanical application board design.

TYPICAL CHARACTERISTICS

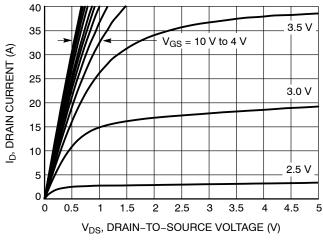


Figure 1. On-Region Characteristics

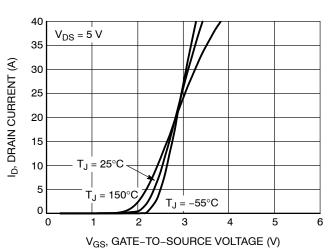


Figure 2. Transfer Characteristics

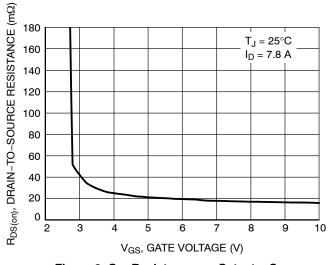


Figure 3. On-Resistance vs. Gate-to-Source Voltage

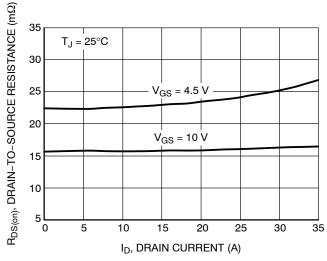


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

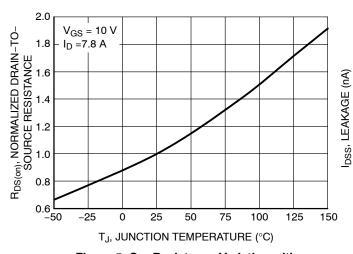


Figure 5. On–Resistance Variation with Temperature

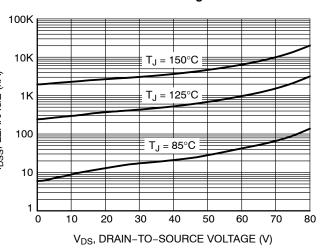


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

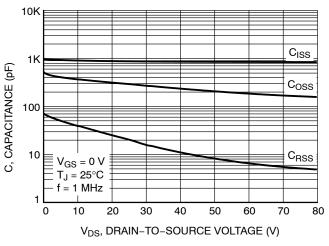


Figure 7. Capacitance Variation

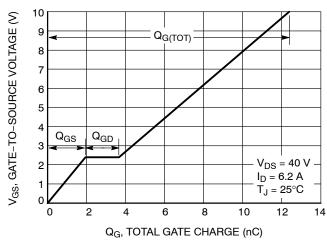


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

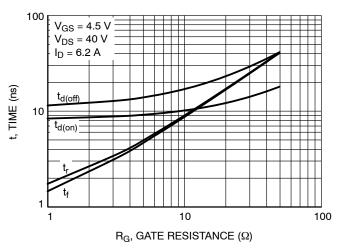


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

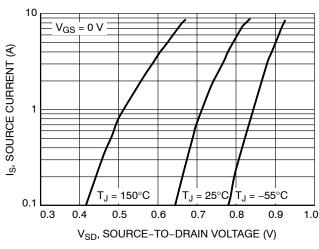


Figure 10. Diode Forward Voltage vs. Current

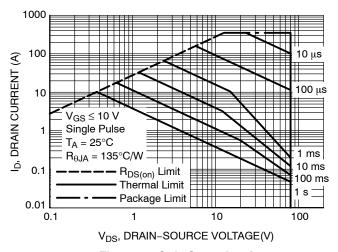


Figure 11. Safe Operating Area

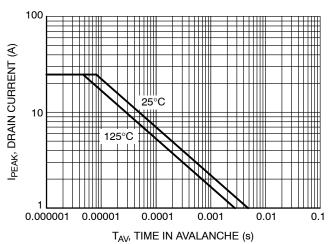


Figure 12. $I_{\mbox{\scriptsize PEAK}}$ vs. Time in Avalanche

TYPICAL CHARACTERISTICS

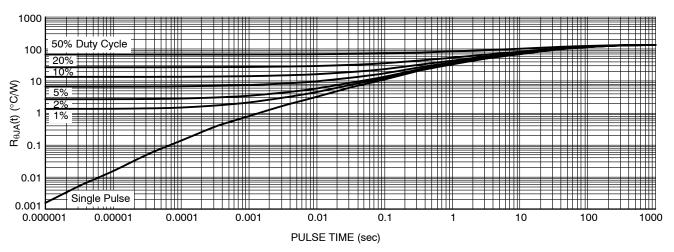


Figure 13. Thermal Characteristics





WQFN12 3.3X3.3, 0.65P CASE 510CJ **ISSUE A**

DATE 08 AUG 2022

MAX

0.80

0.05

0.37

3.40

1.54

0.30

3.40

1.29

0.40

0.64

0.39

0.35

MILLIMETERS

NOM

0.75

0.20 REF

0.32

3.30

1.44

0.20

3.30

1.19

0.30

0.65 BSC

0.325 BSC

1.24 BSC

0.33 REF

0.43 REF

0.54

0.29

0.25

DIM

Α

A1

АЗ

b

D

D2

D3

Ε

F2

E3

е

e/2

е1

k

k1

L

L1

L3

MIN

0.70

0.00

0.27

3.20

1.34

0.10

3.20

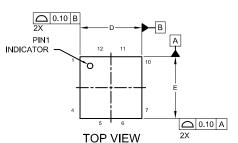
1.09

0.20

0.44

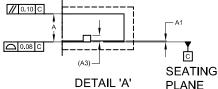
0.19

0.15

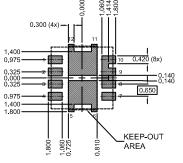


NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
- COPLANARITY APPLIES TO THE EXPOSED
- SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
- 5. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.

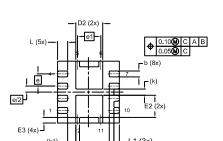


SCALE 2:1



LAND PATTERN RECOMMENDATION *FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.





BOTTOM VIEW

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code = Assembly Location = Year

WW = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "", may or may not be present. Some products may not follow the Generic Marking.

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DESCRIPTION:	WQFN12 3.3X3.3, 0.65P		PAGE 1 OF 1		

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